

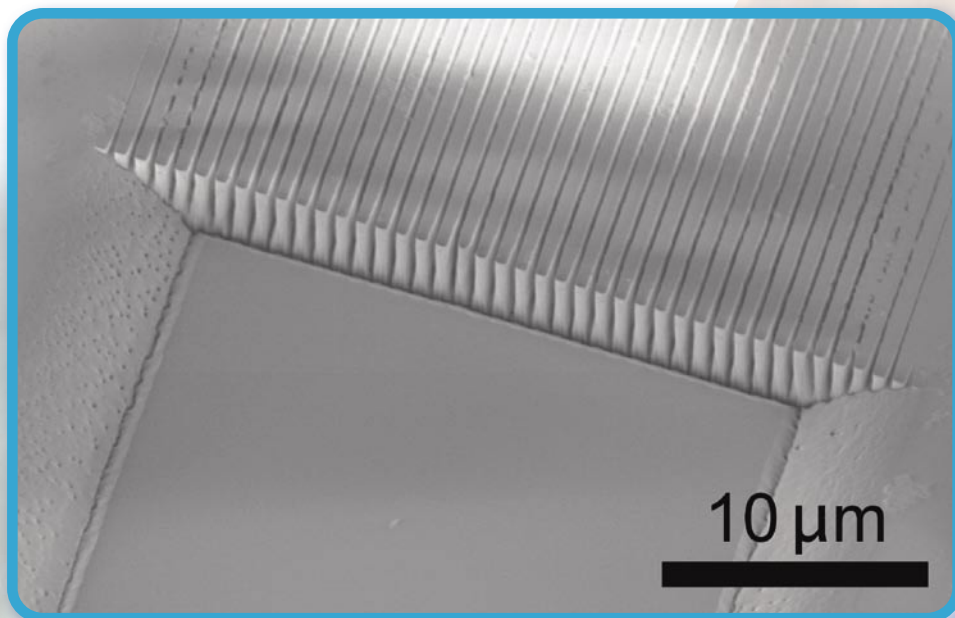
PITTCONTM
CONFERENCE & EXPO
2013 PHILADELPHIA
MARCH 17-21



JJAPAN **S**SYMPOSIUM

March 19 (Tue.), 2013

*The State-of-the-Art Technologies from Japan:
Analytical Instruments with / for Nano-Physics Technology (I) & (II)*



SEM image of the nanowall array structure etched into a quartz substrate.

T. Yasui, N. Kaji, R. Ogawa, S. Hashioka, M. Tokeshi, Y. Horiike, Y. Baba, *Analytical Chemistry*, 83, 6635-6640 (2011).

JAPAN SYMPOSIUM

PITTCON 2013 SYMPOSIUM

March 19 (Tue.), 2013

Place: Pennsylvania Convention Center Philadelphia, PA USA Room: 122B

Morning Session

The State-of-the-Art Technologies from Japan: Analytical Instruments with / for Nano-Physics Technology (I)

– arranged by Koichiro Matsuda, Japan Analytical Instruments Manufacturers' Association (JAIMA)

Koichiro Matsuda, JAIMA, Presiding
Takeshi Kawamoto, JAIMA, Co-Presiding

-
- 8:00 – 8:05 **Introductory Remarks**
Shigehiko Hattori, President of JAIMA
-
- 8:05 – 8:40 **Innovative Nano-Biodevices for DNA and related Molecules: STM and Gating Nanopore**
Tomoji Kawai, Osaka University
-
- 8:40 – 9:15 **Avant-garde femtosecond laser processing: from new phenomena to innovative devices**
Yasuhiko Shimotsuma, Kyoto University
-
- 9:15 – 9:50 **Micro- and Nano-Fluidic Devices for Medical and Life Science Applications**
Manabu Tokeshi, Hokkaido University
-
- 9:50 – 10:25 **Characterization of Micro/Nano Liquid Interfaces**
Akihide Hibara, the Univ. of Tokyo
-
- 10:25 – 11:00 **Towards the Safety and Comfortable Research Environment in University
- Nano-Materials: the Last Potential Hazards in Science -**
Hitoshi Yamamoto, Osaka University
-

Afternoon Session

The State-of-the-Art Technologies from Japan: Analytical Instruments with / for Nano-Physics Technology (II)

– arranged by Koichiro Matsuda, Japan Analytical Instruments Manufacturers' Association (JAIMA)

Koichiro Matsuda, JAIMA, Presiding
Manabu Tokeshi, Hokkaido Univ. Co-Presiding

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- 2:00 – 2:05 **Introductory Remarks**
Hiroshi Nakamura, President of JSAC
-
- 2:05 – 2:40 **Latest SEM Ion/Electron Beam Technologies for Nano-Physics Applications**
Jamil Clarke, Hitachi High-Technologies America, Inc.
-
- 2:40 – 3:15 **Aberration Corrected Electron Microscopy: Structure Determination and Chemistry on the Atomic Scale**
Thomas Isabell, JEOL USA, INC.
-
- 3:15 – 3:50 **Spectroscopic Characterization of Nanoparticles for Potential Drug Discovery**
Mark Talbott, Shimadzu Scientific Instruments Inc.
-
- 3:50 – 4:25 **Contributions of Raman Microscopy to the Characterization of Physical Processes in Nanomaterials**
Fran Adar, HORIBA Jobin Yvon, Inc.
-
- 4:25 – 5:00 **A New X-Ray Scattering Method for Determining Shape of Nanoscale Devices**
Kazuhiko Omote, Rigaku Corporation
-

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